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- 1 The characterisation of dental enamel using transmission Kikuchi diffraction in the scanning
- 2 electron microscope combined with dynamic template matching
- 3
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13 Abstract

14 The remarkable physical properties of dental enamel can be largely attributed to the structure of the 15 hydroxyapatite (HAp) crystallites on the sub-micrometre scale. Characterising the HAp 16 microstructure is challenging, due to the nanoscale of individual crystallites and practical challenges 17 associated with HAp examination using electron microscopy techniques. Conventional methods for 18 enamel characterisation include imaging using transmission electron microscopy (TEM) or 19 specialised beamline techniques, such as polarisation-dependent imaging contrast (PIC). These 20 provide useful information at the necessary spatial resolution but are not able to measure the full 21 crystallographic orientation of the HAp crystallites. Here we demonstrate the effectiveness of 22 enamel analyses using transmission Kikuchi diffraction (TKD) in the scanning electron microscope, 23 coupled with newly-developed pattern matching methods. The pattern matching approach, using 24 dynamic template matching coupled with subsequent orientation refinement, enables robust 25 indexing of even poor-quality TKD patterns, resulting in significantly improved data quality 26 compared to conventional diffraction pattern indexing methods. The potential of this method for the 27 analysis of nanocrystalline enamel structures is demonstrated by the characterisation of a human 28 enamel TEM sample and the subsequent comparison of the results to high resolution TEM imaging. 29 The TKD – pattern matching approach measures the full HAp crystallographic orientation enabling a 30 quantitative measurement of not just the c-axis orientations, but also the extent of any rotation of 31 the crystal lattice about the c-axis, between and within grains. Results presented here show how this 32 additional information highlights potentially significant aspects of the HAp crystallite structure, 33 including intra-crystallite distortion and the presence of multiple high angle boundaries between 34 adjacent crystallites with rotations about the c-axis. These and other observations enable a more 35 rigorous understanding of the relationship between HAp structures and the physical properties of

- 36 dental enamel.
- 37

38 Keywords

- 39 Enamel, Hydroxyapatite, Biomineralisation, Transmission Kikuchi Diffraction (TKD), Pattern
- 40 Matching, Dynamic Template Matching.
- 41

42 1. Introduction

43

44 Dental enamel is the outermost layer of the tooth that covers and protects the underlying dentine.

45 Unlike other mineralised tissues, dental enamel is acellular and hence lacks the ability to regenerate

- 46 or repair itself following traumatic events or pathological decay [1; Robinson et al., 2000]. Due to its
- 47 acellular composition, dental enamel emerges as the hardest and most mineralised tissue in the
- 48 human body [2; Robinson et al., 1995a] comprising of up to 98 wt. % mineral [3; Elliott, 1997]. The
- 49 mineral content had been identified as an impure, non-stoichiometric, calcium deficient, carbonated
- 50 hydroxyapatite (HAp) [3; Elliott, 1997] in the form of needle-like crystallites measuring

approximately 26 nm in thickness, 68 nm in width and up to several microns in lengths [4; Kerebel et

- 52 al., 1997]. These crystallites are tightly packed into bundles, known as prisms, in the order of 4-7 μ m
- 53 in diameter extending from the enamel-dentine junction to the enamel surface [5-6; Simmer et al.,
- 54 2012; Shore et al., 1995a]. In human enamel, the cross sections of the majority of these prisms
- resemble a keyhole shape with distinct head and tail regions [6-7; Shore et al., 1995a; Boyde, 1964].
- 56 The visualisation and assessment of intra-prismatic crystallite organisation and alignment are critical

to gain complete understanding of the properties and structure of dental enamel and the underlying

58 mechanisms of enamel biomineralisation and its relationship to dental health. This information can

assist in the identification of potential causes of enamel defects and disorders and provide insight

60 into the tooth response to the various types of forces and stresses it is subjected to during biting and

61 mastication [8; Lawn et al., 2010].

62 Early studies examining the arrangement of crystallites within prisms in enamel have primarily

63 utilised electron microscopy techniques. It has been observed that the c-axes of the crystallites at

64 the head are predominately oriented parallel to the long axis of the prism, with minor variations.

65 However, the crystallites in the tail region are angled at approximately 45-70° to the direction of the

prism long axis [6, 9-11; Shore et al., 1995a, 1995b; Robinson et al., 1995b; Poole and Brooks, 1961].

67 Recent advances in imaging techniques have provided new insights into the organisation,

68 orientation, and properties of intra-prismatic crystallites. Recent studies using polarisation-

69 dependent imaging contrast (PIC) mapping to assess human enamel with a pixel size range of 22-

- 57 nm along the normal of the sample surface suggested that the long axis of each crystallite is not
- always co-aligned in the head region; they can be as much as 90° apart [12; Beniash et al., 2019]. It
- was concluded that the observed mis-orientation is most likely a crack-deflecting and toughening
- 73 mechanism against the high loading forces resulting from biting and mastication [12-13; Beniash et
- al., 2019; Stifler et al., 2021]. It is important to note that the PIC mapping technique can only assess
- the enamel surface to a depth of 3 nm, with 1 nm of this being a Pt coating and it only provides the
- 76 c-axis crystal orientations of HAp and not the full crystal orientation. Given that the typical
- dimensions of HAp crystallites in enamel are significantly larger [4; Kerebel et al., 1979], it is
- 78 questionable whether the technique is capable of providing accurate data on enamel structure. Free
- 79 et al. used a combination of synchrotron X-ray diffraction, crystallite orientation analyses, and
- machine learning to investigate the intra-prismatic variations in crystallographic parameters in
 enamel. Their study revealed distinct compositions among inter-prismatic crystallites. It is worth
- 82 noting that the step size of 500 nm utilised, while capable of identifying intra-prismatic features, is
- still markedly larger than the typical size of an individual crystallite [14-15; Free et al., 2020; 2022].
- 84 One technique that does provide full crystallographic orientations with a sub-100 nm spatial
- 85 resolution is electron backscatter diffraction (EBSD). EBSD is a scanning electron microscope (SEM)

86 based technique that is used extensively for the characterisation of crystalline microstructures, 87 including metals, alloys, ceramics and minerals [e.g. 16-17; Zaefferer, 2011; Borrajo-Pelaez and 88 Hedström, 2017]. The spatial resolution of EBSD is typically quoted as being in the order of 50-100 89 nm, but this is often a measure of the "effective" spatial resolution, influenced by the analysis 90 software's ability to deconvolve overlapping diffraction patterns from neighbouring crystallites. The 91 true spatial resolution of the technique can be significantly poorer, especially at higher beam 92 energies or for the analysis of low atomic number materials. For example, for Mg, previous work has 93 indicated a true EBSD spatial resolution of ~600 nm at 15 keV beam energy, with an even worse 94 resolution down the steeply tilted surface that is required for conventional EBSD [18; Tripathi & 95 Zaefferer, 2019]. Given that HAp has a comparable atomic number to Mg, it is reasonable to expect 96 a similar spatial resolution for the EBSD analysis of HAp microstructures. There have been a number 97 of studies showing the potential of EBSD to characterise apatite-based microstructures, such as for 98 the study of conodont fossil structures (e.g. 19-20; Pérez-Huerta et al., 2012, Atakul-Özdemir et al. 99 2021) or in studies of shocked microstructures (e.g. 21; McGregor et al., 2021). However, these all 100 involve microstructures on the scale of 10s to 100s μ m, for which the spatial resolution of EBSD is

101 sufficient and the effect of electron beam damage can be minimised.

102 However, the sub-µm size and distorted nature of HAp crystallites in tooth enamel make EBSD 103 analyses exceptionally challenging, as the source volume for each diffraction pattern is likely to 104 include orientations from multiple adjacent crystallites, thus significantly reducing the quality of any 105 resulting diffraction pattern. There has, therefore, been no reported successful EBSD analysis of 106 tooth enamel. A variation of EBSD, transmission Kikuchi diffraction (TKD), does hold much more 107 promise for the analysis of HAp structures in enamel. TKD, also sometimes referred to as 108 transmission EBSD (t-EBSD), involves the collection of Kikuchi diffraction patterns from an electron 109 transparent sample such as is typically prepared for imaging and analysis using the transmission 110 electron microscope (TEM). In TKD the diffraction pattern is projected from the lower (exit) surface

- 111 of the sample and this can be imaged either using a conventional EBSD detector with a (sub-) vertical
- 112 phosphor screen, or using a specially modified detector with a horizontal phosphor screen ("off-axis"
- and "on-axis" TKD geometries, respectively) (22-25; Geiss and Keller, 2012; Trimby, 2012;
- 114 Fundenberger et al., 2016; Sneddon et al., 2016). The major advantage of TKD over conventional
- EBSD is the spatial resolution: with suitably thin samples, a lateral spatial resolution of sub 10 nm
- 116 has been demonstrated in various studies (e.g. 26; Shen et al., 2019), significantly better than is
- 117 possible with conventional EBSD. This makes TKD a potentially powerful technique for the analysis of
- the nanostructured HAp crystallites in enamel, although the sensitivity of the material to damage
- 119 from the electron beam could limit the achievable spatial resolution in practice.

120 Two reported studies have already used TKD on enamel structures (27-28; Koblischka-Veneva et al., 121 2018; 2019). These showed that the TKD method does enable the collection of indexable diffraction 122 patterns, however the results in both studies are questionable. For example, the diffraction pattern 123 and corresponding indexed solution shown in one study (Figure 7 d-e and Supplementary figure S1, 124 27; Koblischka-Veneva et al., 2018) clearly indicates incorrect indexing, with no correlation between 125 the observed and simulated Kikuchi bands. The subsequent orientation maps, despite a remarkable 126 5 nm step size, also show little correlation to the observed structures in corresponding TEM images 127 from the same samples, once again indicating poor or incorrect indexing possibly compounded by 128 over-aggressive data cleaning. This is further backed up by the blocky morphology of the crystallites 129 in the TKD orientation maps, with unusually straight boundaries between crystallites and no 130 evidence of the systematically elongated structures visible in the TEM images (e.g. Figures 2 and 3a, 131 28; Koblischka-Veneva et al., 2019). A lack of a reference image from the TKD-mapped area (such as a diffraction pattern quality map or a bright- or dark field electron image) makes it difficult to haveany confidence in the veracity of these data.

134 In this work we revisit the use of TKD for the characterisation of tooth enamel nanostructures. As 135 demonstrated by Koblischka-Veneva and colleagues, TKD in the SEM does enable the collection of 136 indexable diffraction patterns. However, the pattern quality is highly variable and therefore newly-137 developed pattern matching indexing and refinement methods may be necessary for effective 138 mapping of typical HAp microstructures. Such pattern matching methods use comparisons between 139 experimental diffraction patterns and simulated patterns that are generated using dynamical 140 modelling methods (e.g. 29-30; Winkelmann et al., 2007; Winkelmann, 2009). The first developed 141 pattern matching methods focused on dictionary indexing, in which a large precalculated library of 142 simulated patterns covering all possible crystallographic orientations would be compared to each 143 experimental pattern, with the best fitting template selected and the corresponding phase and 144 orientation saved (e.g. 31; Chen et al., 2015). This method was extremely time consuming and 145 resulted in a relatively low orientation precision, but it was demonstrated to give far better indexing 146 rates than conventional Hough-based indexing on samples that produced poor quality diffraction 147 patterns (e.g. 32; Singh et al., 2018). Other approaches have utilised a hybrid approach, in which 148 simulated diffraction patterns were calculated as required, based on the initial orientation from 149 Hough-based indexing (e.g. 33-35; Winkelmann et al., 2020; Winkelmann and Nolze, 2015; Nolze et 150 al., 2018). This approach enabled on-the-fly refinement of the orientation at each point, as well as 151 testing against pseudosymmetrically equivalent orientations, structure inversions or even against 152 phases with similar structures (e.g. 36; Nolze et al., 2017). Such pattern matching approaches have 153 developed in usability and speed since first being proposed and now offer a range of benefits 154 compared to conventional Hough-based indexing, both in terms of better indexing of poor quality 155 diffraction patterns as well as potentially a higher accuracy and precision in the final data.

156 Consequently, in this work we are exploring the further application of TKD, coupled with the latest 157 advances in pattern matching technology, to the study of dental enamel, which could assist in 158 elucidating new features of this complex, hierarchical structure. This research could have significant 159 implications for treating dental diseases and informing emerging biomimetic technologies that aim 160 to create materials that mimic the enamel microstructure.

- 161
- 162 2. Material and Methods

163

164 2.1 Sample Selection and Preparation

165 A healthy human premolar was obtained with ethical approval from the Leeds School of Dentistry

166 Tissue Bank (ref: 091219/MA/293). The tooth was embedded in fast curing acrylic cold mounting

resin (ClaroCit, Struers, Ballerup, Denmark) and cut mesio-distally through the mid-point into 2

halves using a Struers Accutom-10 diamond saw (Struers, Willich, Germany). The cut surface of the

buccal half of the tooth was then wet-ground using finer grades (100-, 220-, 320-, 400- and 600-grit)
of silicon carbide abrasive papers placing the tooth in distilled water between successive grits. The

171 cut surface was then etched using 20% orthophosphoric acid for 15 seconds.

172 The embedded section was washed with distilled water and secured onto an aluminium stub using

173 carbon adhesive disk. A 20 nm iridium coating was applied to eliminate contaminations [37; Xu et al.,

174 2022] and the resin and stub were carbon coated to avoid charging.

175 2.2. TEM Sample Preparation

For TEM imaging and TKD analysis, a thin sample lamella was prepared via the in-situ lift-out method
using a FEI Helios G4 CX dual beam, high resolution monochromated, field emission gun SEM with
precise focused ion beam (FIB-SEM).

179 Using the secondary electron detector, a region of interest (ROI) was identified and selected in a manner that ensured it was contained within the prism head and aligned with its long axis (Figure 1). 180 181 In the FIB-SEM chamber, a 200 nm strip of platinum (Pt) was electron beam deposited (at 5 kV, 6.4 nA for the electron source) onto the ROI ($100 \times 20 \mu m$) on the sample surface. This was followed by 182 183 a second Pt layer (2 μm) using ion assisted deposition of a Pt ion-rich precursor gas (at 30 kV, 0.23 nA 184 for the liquid gallium (Ga) ion source) at a 52° angle to the vertical electron beam. The Pt protective 185 layer dramatically decreases curtaining artefacts in the cross-sectioned enamel surface [38; Ishitani 186 et al., 2004] and protects the sample surface during milling [37; Xu et al., 2022]. The chamber 187 pressure was maintained to approximately 2×10^{-6} mbar (increases to 5×10^{-5} mbar during Pt 188 deposition). An initial lamella was cut (via FIB milling at 30 kV, 21 nA), before a final cut-out was 189 performed (at 30 kV, 0.79 nA). Final thinning and polishing of the lamellae to electron transparency 190 was performed with a low energy ion beam (5 kV, 41 pA). The lamella was then lifted using a 191 micromanipulator and welded using ion beam deposited Pt onto a copper FIB lift-out grid 192 (Omniprobe, Oxford Instruments, UK). The thickness of the lamella was measured using high

resolution electron imaging in the FIB-SEM and varied between 70 and 100 nm.



194

195 **Figure 1.** Sample preparation for TEM and TKD using FIB milling and micromanipulation: (a) A

196 photograph of the sample in the FIB-SEM chamber. (b) SEM image showing the etched surface of the

enamel sample with visible prismatic structure. Scale bar 20 μm. (c) A magnified SEM image of (b).
Scale bar 10 μm. (d) The region of interest is shown coated with Pt. Scale bar 10 μm. (e, f) Milled out

- area around the ROI. Scale bars 20 μm. (g) Welded lamella to the tip of a grid prior to thinning. Scale
 bar 10 μm. Final sample lamella after thinning to 70-100 nm viewed from (h) front and (i) top-down
 perspective. Scale bars 5 μm. PH: Prism head. PT: Prism tail. ES: Enamel surface.
- 202 2.3 SEM Imaging

203 The FIB-prepared sample was mounted onto an Omnipivot[™] sample holder with a pre-tilt angle of

45° (backtilted). This was inserted into a Carl Zeiss Gemini 460 field emission gun SEM, with the

stage tilted to 45° so that the TEM sample was in a horizontal position. The sample chamber was

briefly cleaned using an integrated, chamber-mounted Evactron plasma cleaner (2 minutes at 20W
power) before the sample was positioned at a working distance of 8.6 mm.

- 208 The electron beam accelerating voltage was set to 30 kV, with a beam current of 3.9 nA, and the
- 209 EBSD detector (Symmetry S3 detector, Oxford Instruments) was positioned to the fully inserted

210 position. The lower forescatter detectors (3 backscattered electron (BSE) diodes mounted below the

211 phosphor screen of the EBSD detector) were then used to generate dark field electron images (e.g.

- Trimby et al., 2014) with 2046 x 1641 pixel resolution and a 60 μ s dwell time for each pixel. The
- 213 scanning, image selection and subsequent TKD data collection were carried out using Oxford
- 214 Instruments' AZtec software, v6.0.

215 2.4 TKD Analysis

216 Following imaging, a suitable area in the thinnest part of the sample was selected for TKD analysis.

The EBSD detector was set to "Speed 1" mode (622 x 512 pixel resolution), using a low electronic

218 gain setting and a 100 ms exposure time for each diffraction pattern. A background image was

- collected from the whole sample and was used, along with dynamic background correction, to
- 220 improve the quality and uniformity of the signal in the TKD patterns. An area of 3 x 4 μ m was

analysed with a measurement step size of 20 nm and at an analysis rate of 9.3 measurements per

- second (the total analysis time was just under 54 minutes). The TKD patterns were analysed using a standard Hough-transform approach to detect the Kikuchi bands, using a full Hough resolution of
- 121 (60 in the AZtec software) and using the AZtec software's "Optimized Band Detection" mode.
- The indexing was carried out with reference to a HAp structure (Space Group 176, P $6_3/m$, unit cell a

226 = b = 9.4373 Å, c = 6.8881 Å) using 48 theoretically calculated reflectors. During the analysis the TKD

- 227 patterns at each measurement point were stored for further offline examination.
- 228 2.5 Reanalysis using Pattern Matching

229 The original TKD data, along with the stored TKD patterns, were exported into the Oxford

230 Instruments *.h5oina data format [39] which utilises the hierarchical data format 5 (HDF5) structure.

231 The data were loaded into the Oxford Instruments AZtecCrystal software (version 3.1) for further

processing using pattern matching methods, included as part of the "MapSweeper" functionality.

Firstly, a master simulation file for HAp was created, using the crystallographic information file (cif)
number 1526459 downloaded from the Crystallography Open Database [40] and based on the HAp

235 structure reported in [41; Ivanova et al., 2001]. Four additional HAp structures and compositions

- (with trace amounts of Na and Mg), as described in Wilson et al. (1999) (labelled RGB, RQ1, RE1 and
- RC1), were also used to create master simulations in order to test the influence of minor chemical
- and structural variations; these had a negligible effect on the simulations and no discernible impact
- on the pattern matching results (<1 % difference), so the initial HAp structure was used. The master
- simulation file is a model of the electron diffraction intensities for all crystallographic orientations of
 HAp, for a specific beam energy (here 30 kV). A full many-beam dynamical simulation method was

- used, as described in Winkelmann (2009), with the following modelling parameters minimum
- intensity 20%, minimum lattice spacing 1.2 Å, Debye Waller factor 0.5 and a full resolution of 501 x
- 244 501 pixels. This master file typically takes approximately 5 minutes to create and is then valid for use
- on all subsequent datasets for the specified phase, collected using the same beam energy.

246 During all stages of the pattern matching process, pattern templates (e.g. simulated TKD patterns) 247 for desired phases and crystallographic orientations are derived from the master simulation file, 248 using the local projection geometry for the analysis point in question, and are created at the desired pixel resolution (either low resolution for initial indexing, or high resolution for calibration or for 249 250 orientation refinement). Each pattern template, as well as the experimental TKD pattern, was 251 weighted using a 2D Gaussian window function in order to give greater importance to the centres of 252 the patterns (where the experimental patterns have a higher signal to noise ratio) compared to the 253 noisier edges of the patterns. This weighting also minimises the impact of shadowing in the 254 experimental data, a common problem with off-axis TKD. The process is fully dynamic: templates are 255 not stored on disk but are, once generated, matched directly to the experimental diffraction pattern 256 to give a metric of image similarity and are then discarded. Here we use the normalised cross 257 correlation coefficient (R) to assess the quality of pattern matching (e.g. 42; Goshtasby, 2012). The 258 absolute value of R can range from 0 to 1, with a higher R value indicating a better match. As any 2 259 arbitrary images can be correlated and will give an absolute R value > 0, it is essential that a 260 minimum threshold level of R is used: here we used a threshold of R = 0.15 to ensure the reliability 261 of the orientation measurements. This threshold level has been chosen to provide the best balance 262 between a high indexing rate and a good level of data reliability.

263 For each analysis point, the Nelder-Mead optimisation method was used to refine the orientation 264 measurement as follows (43; Nelder and Mead, 1965). Small variations in the crystallographic 265 orientation, deviating from the originally measured orientation, were considered in order to create 266 new pattern templates: each of these were matched against the experimental TKD pattern and a 267 new R value was calculated. This process was repeated to maximise the R value, until successive 268 measurements generated R values differing by less than a pre-determined threshold, in this case < 269 0.0005. This orientation refinement process results in measurements with a significantly higher 270 angular precision than those measured using conventional Hough-based indexing, as described in 271 [35] Nolze et al. (2018).

- 272 The HAp structure belongs to the low hexagonal Laue group (6m) and, as such, lacks the basal mirror 273 plane of high hexagonal phases. However, the HAp structure is close to having high hexagonal 274 symmetry and therefore, for example, the diffraction patterns for the <0001> (+c) direction are very 275 similar to those for the <000-1> (-c) direction (referred to as pseudosymmetry). This can, for some 276 crystallite orientations, result in systematic misindexing of the TKD patterns when using the Hough 277 transform indexing method. Therefore each TKD pattern was also matched against templates for the 278 pseudosymmetry related orientation, defined by an orientation rotation of 180° about <-1-120>, in 279 order to determine the correct orientation (i.e. the solution with the highest R value). An additional 280 pseudosymmetric relationship, represented by a 90° rotation about the <-12-10> axis, was also 281 tested and corrected in the same way.
- Many of the processes used for the generation and correlation of templates in such a dynamic way,
 such as the orientation refinement and the testing for pseudosymmetry, have been described in
 earlier hybrid pattern matching work, such as in [33] Winkelmann et al. (2020).
- In order to ensure high-precision results, the pattern matching method requires a very goodcalibration of the projection geometry for each diffraction pattern. Therefore, prior to reanalysis, the

- calibration parameters were refined as follows, using a similar approach to that described in earlier
 work (e.g. [33, 44]; Winkelmann et al., 2020; Friedrich et al., 2018):
- 8 points were manually selected across the analysed area on the basis of having relatively
 good quality diffraction patterns. Although this process can be automated, in this case the
 generally poor diffraction pattern quality within the dataset necessitated manual point
 selection. Points were chosen that had been successfully indexed using the Hough transform
 indexing method.
- As described above, for each calibration point the pattern matching process would be used to refine the solution and to test against the pseudosymmetrically related solutions.
 However, during the optimisation process, changes to the projection geometry (i.e. the pattern centre position and the detector distance) would also be adjusted to find the optimal values.
- The refined calibration parameters were then used to calculate optimal calibration values
 for each point in the TKD dataset.
- 301

Using the improved calibration parameters, the dataset was then reprocessed using a dynamic 302 303 template matching (DTM) approach to indexing. The step by step process of DTM indexing and 304 subsequent orientation refinement is schematically illustrated in a flow diagram, Figure 2. Following 305 the initial data collection, master pattern simulation and calibration geometry refinement (e.g. steps 306 1 – 2 in Figure 2), the following process was carried out. At each point, the experimental TKD pattern 307 was matched against simulated TKD pattern templates for the HAp phase for all possible 308 orientations: no orientation data derived from Hough-based indexing were used in this process (i.e. 309 any pre-existing indexing result was disregarded) - steps 3 - 8. The pattern templates were 310 generated using the calibration parameters at each point and with an orientation spacing of 2°. Note 311 that the templates are not stored on disk, with each one created and then the normalised cross 312 correlation coefficient between the template and the experimental Kikuchi pattern is calculated on-313 the-fly on the GPU, and then the template is discarded. Although the dictionary indexing method can 314 also be used in a "dynamic" way (e.g. [46] Jackson et al., 2019), this involves precalculating blocks of 315 simulated templates which are then passed to a GPU for the pattern matching process. The DTM 316 approach is truly dynamic, with each simulated template only created when needed, giving the 317 technique a greater flexibility in terms of the subsequent solution refinement, as described below. A 318 template resolution of 38 x 32 pixels was used, and the experimental pattern at each point was also 319 binned down to the same pixel resolution. As in the dictionary indexing method, the simulated 320 template that produced the highest cross correlation coefficient (R) was selected as the correct 321 orientation (step 9). The initial DTM indexing method, as for dictionary indexing, produces 322 discretised orientation measurements at the initial orientation spacing, here 2°. However, the 323 dynamic nature of the method enables a subsequent orientation refinement process to be carried 324 out immediately, using the optimisation approach described previously (steps 10 - 14). Unlike the 325 initial DTM indexing, this orientation refinement was carried out at a higher pattern resolution (both 326 experimental and simulation), 321 x 256 pixels, binned down by a factor of 2 from the stored TKD 327 patterns. Once again, the patterns were also matched to simulations corresponding to the 328 pseudosymmetrically equivalent orientations to eliminate any systematic misindexing (step 13).



Figure 2. The step by step procedure for TKD pattern indexing using the DTM method, with
 subsequent orientation refinement. See text for full details.

332 The process was then repeated for all points in the dataset: due to the relatively large numbers of

templates being generated at each point (typically ~200,000), the analysis speed is significantly

increased by use of a graphical processing unit (GPU). In this case a low specification NVIDIA GeForce

GTX 1050 Ti GPU was used (4 Gb memory, 768 CUDA Cores), enabling an indexing and refinement
 speed of ~8 patterns per second.

337 An additional method, following the DTM indexing and subsequent orientation refinement, was also 338 used to improve the indexing rate of the dataset and to remove any potentially incorrect (misindexed) measurements. Although the DTM process (as with dictionary indexing) is far less likely 339 340 to generate incorrect solutions than the conventional Hough-based indexing method, the poor 341 quality patterns, low pattern resolution during the DTM process (38 x 32 pixels) and the 2° 342 orientation spacing between templates can all result in isolated indexing errors. This "Repair Sweep" 343 within the MapSweeper software uses the indexed orientation of neighbouring pixels as the starting 344 orientation for the template simulation. In this way isolated orientations (or small clusters of 345 orientations, with an area of 5 pixels or smaller) were checked against neighbouring measurements, 346 either validating the original indexed solution or correcting them to an orientation close to that of adjacent points, based on which gave the highest R value. Likewise, the stored TKD patterns at non-347 348 indexed points were compared to simulated templates generated using the orientations of 349 neighbouring, indexed points and accepted if the final refined solution had an R value exceeding the 350 0.15 threshold. This repair process was also carried out at a higher resolution than the initial DTM 351 indexing process (using a 321 x 256 pixel resolution) and so some improvements were typically made 352 to the DTM indexed data (in this case, 2015 measurements were modified, including 236 points that 353 were previously unindexed and 1779 points (~ 6% of the whole dataset) that had their orientation 354 changed). As before, the orientation measurements were refined and the final result was only 355 accepted if R > 0.15. This method ensures that map points with patterns which do not allow a 356 reliable indexing are assigned as zero solutions due to the correspondingly low R values, and that no 357 orientation data were interpolated from existing measurements (e.g. as derived from Hough 358 transform indexing). In each step of the DTM method, the orientation refinement and the 359 subsequent Repair Sweep, the underlying experimental pattern at each pixel is the fundamental 360 source of the derived orientation and phase solution. At no point during the DTM indexing, 361 refinement and subsequent repair process were the full 622 x 512 pixel resolution TKD patterns 362 used: this was in part because of the relatively poor quality of the HAp patterns but also because the 363 process of pixel binning within the software results in an improvement in the signal to noise ratio in the patterns. The refinement and repair steps would have been slower if using the full resolution, 364 365 with no corresponding benefit in precision or accuracy of the final result.

366 An example of the pattern matching is provided in Figure 3. Here, in Figure 3a, a relatively high 367 quality TKD pattern from within a HAp crystallite is shown with the best fit matching template for 368 both the originally indexed orientation (from the DTM indexing process and subsequent refinement) 369 and the rotated, pseudosymmetric solution (Figure 3b). The similarities between the 2 solutions are 370 clearly visible, but the presence or absence of simulated Kikuchi bands for each solution results in a 371 significant difference between the normalised cross correlation coefficient (R = 0.5317 compared to 372 R = 0.5000), with the original orientation matching best. In Figure 3c the result for a poorer quality 373 TKD pattern is shown: with an R value of 0.2054, this still exceeds the minimum threshold for 374 acceptable pattern correlation (R = 0.15). Such a poor quality pattern would not be indexed using 375 conventional Hough-based indexing methods, thus demonstrating the robustness of the DTM 376 indexing process.



Figure 3. Example pattern matching results for good and poor quality TKD patterns from HAp
 crystallites. Left – experimental TKD pattern. Centre – best fitting dynamical simulation. Right –
 difference between experimental and simulated patterns. Scales are given in standard deviations

381 from the mean value within each image. (a) TKD pattern 1: best fitting orientation, with a normalised

382 cross correlation coefficient, R = 0.5317. (b) TKD pattern 1: the equivalent pseudosymmetric

- orientation, rotated 180° about <-1-120>, with R = 0.5000. (c) TKD pattern 2: an example of a poor
- 384 quality TKD pattern, still with robust indexing, albeit with a lower R value (R = 0.2054).

Following completion of the pattern matching reanalysis, which took a total of ~70 minutes, the data were stored as a new dataset for further analysis within the AZtecCrystal software.

387 2.6 Data Processing

388 The enhanced data following the reanalysis using pattern matching were then processed using the

- 389 data analysis tools within the AZtecCrystal software. The data were firstly cleaned using a single
- 390 iteration of the "AutoClean" function: this removes isolated orientation measurements and
- 391 performs a 2-pass clean up, replacing non-indexed pixels with adjacent, indexed values for pixels
- 392 firstly with 6 indexed neighbours and then 5 indexed neighbours. This ensures that more complete
- 393 boundary information between grains can be calculated.
- 394 Following cleaning, routine analyses of the data were performed in order to determine the grain size
- and shape, the texture (or crystallographic preferred orientation), the extent of deformation or
- intra-crystallite strain and to map out the key microstructural characteristics of the HAp crystallites
- 397 within this enamel sample.
- 398

399 2.7 TEM Imaging

TEM analyses were carried out using a FEI Titan3 Themis G2 S/TEM operated at 300 kV with a Gatan
OneView 16 Megapixel CMOS digital camera for collecting bright-field TEM images. The TEM images
were collected at a screen current of 3 nA.

403 Note that the earlier TKD analyses caused noticeable damage to the TEM sample. At each point

analysed by TKD, a damage spot was clearly observable in the subsequent TEM images. Although the
 damage spots enabled easy correlation between the TEM images and the TKD results, they also

405 obscured some of the HAp structures and thus most TEM imaging was performed on areas

407 immediately adjacent to the TKD analysis region. A discussion about the potential impact of the

408 beam damage during the TKD analysis is provided in the discussion section.

409

410 **3. Results**

411 A forescatter detector (FSD) darkfield image of the FIB-prepared sample is shown in Figure 4. The

412 contrast has been enhanced to highlight the signal variations within the mapped area (marked by

413 the white box) – some minor thickness variations due to the FIB milling are visible as vertical

414 curtains. The image provides some indication of the HAp crystallite size and shape, with elongated

415 crystallites visibly aligned horizontally in the image, with an approximate length of a few hundred

nm. Towards the upper part of the area, as marked by the white arrows, a linear series of voids

417 appears to separate 2 domains with differing crystallite alignments, labelled in Figure 4 as domain A

418 and B.



- Figure 4. A forescatter detector (FSD) darkfield image of part of the FIB-prepared sample showing the general crystallite structure within the enamel. A boundary between 2 domains differently oriented HAp crystallites is approximately marked by a series of voids, highlighted by the white arrows. The domains are labelled A and B (refer to the text for details). The white box marks the TKD analysis area. Note that the contrast has been stretched to enhance the crystallographic contrast, making the thinnest area at the top of the image appear black. The sample thickness increases towards the lower edge of the image resulting in a stronger ESD signal
- 426 lower edge of the image, resulting in a stronger FSD signal.
- 427 The TKD mapping highlights these structural features more clearly. The band contrast map (Figure
- 428 5a), a measure of the quality of the TKD pattern at each point, shows the general crystallite structure
- 429 across the area and clearly emphasises the difference between the 2 domains, based on the
- 430 crystallite size and shape. Towards the lower part of the area the pattern quality dropped off
- 431 significantly, primarily due to an increased sample thickness in these regions coupled with some
- 432 shadowing effects from the thicker margins of the FIB-prepared sample.





Figure 5. Results of TKD mapping of the enamel HAp crystallites. (a) Band contrast (diffraction
pattern quality) map – lighter shades indicate higher contrast (stronger) TKD patterns. (b)
Orientation map following convention Hough-transform indexing: the inverse pole figure colouring

437 scheme shows the crystal direction parallel to the surface normal (IPF-Z) and is superimposed over

- 438 the band contrast map initial indexing success rate 29.1%. (c) IPF-Z orientation map following
- 439 indexing using dynamic template matching, with only minor subsequent data cleaning (see text for
- 440 details) indexing success rate 71.8%, rising to 80.4% after cleaning. The two clearly distinct domains
- 441 are labelled A and B, high angle boundaries >10° are marked in black, low angle boundaries (2-10°) in
- 442 grey and boundaries within 10° of a 30° rotation about the <0001> axis are marked in red. The
- boundary fractions in the legend refer to (c) only. The scale bar in each image marks $1 \mu m$.

The initial indexing rate using the Hough transform method was only 29.1%, with the orientation
map shown in Figure 5b. Although this does provide evidence of different textures in the upper and

- 446 lower domains (as indicated by the different colours using the inverse pole figure colouring scheme),
- the low indexing rate prevents reliable analyses of the crystallites or any local variations in
- orientation. However, following the pattern matching reanalysis, the quality of the data is
- dramatically enhanced; here the indexing rate (without any further data cleaning) is 71.8% and the
- 450 crystallites across most of the mapped area are effectively resolved (Figure 5c). In this map the 2
- 451 aforementioned domains are clearly visible and are labelled "A" and "B". Following the auto-clean
- 452 process in AZtecCrystal, an additional 8.6% of originally unindexed pixels were assigned the
- 453 orientation value of a neighbour, resulting in 80.4% of all measurement points having orientation
- data. This is sufficiently high to be able to measure reliably the crystallites and their orientations,
 boundaries within and between crystallites and to characterise the intra-crystallite deformation.
- Figure 6 shows the texture (or crystallographic preferred orientation) of the HAp crystallites in this
 area represented in pole figures, plotting the poles to the {0001} and {10-10} planes; each
 measurement is plotted using the corresponding colour from the orientation map, Figure 5c. The
 {0001} pole figure shows 2 notable clusters that correspond to the domains (A and B) visible in
 Figure 5c. The c-axes in domain A are oriented at a significant angle to the plane of the sample, ~35°,
 whereas in domain B they are closer to the plane, at ~15°. The {10-10} pole figures show that, for
- 462 both domains, there are 2 sub-clusters of orientations rotated 30° about <0001> from each other, as
- shown by the yellow and purple colours (for domain A) and the green and blue colours (for domainB) in both Figure 6 and Figure 5c. These orientations, for domain B, are illustrated by the unit cell
- displays in Figure 6. The boundaries corresponding to these 30° rotations about the c-axis have been
- 466 coloured in red in Figure 5c: over the whole area, ~21.2% of all high angle boundaries (here defined
- 467 as those with a disorientation angle > 5°) have a disorientation angle and axis within 10° of this 30°
 468 <0001> relationship.



469

- 470 *Figure 6.* Pole figures derived from the TKD measurements of HAp orientations, showing the poles to
- 471 the {0001} planes (left) and poles to the {10-10} planes (right) (upper hemisphere). Each point
- 472 corresponds to an individual measurement and the colour scheme is the same as used in the TKD
- 473 orientation map in Figure 5c. The clusters corresponding to domains A and B are highlighted in the
- 474 {0001} pole figure. Example 3D unit cell orientations (in the same reference frame as the images and
- 475 TKD maps) are shown to the right, corresponding to typical orientations within domain B that are
- 476 related by a 30° rotation about the c-axis.
- 477 The texture of the crystallites can also be visualised using texture component maps. In Figure 7a, the
- deviation of the c-axis orientation of each point away from the average c-axis orientation for all
- 479 crystallites in domain B is plotted, up to a maximum deviation of 45°. This shows that most
 480 crystallites within domain B have their c-axes within 15° of this average orientation, whereas those
- 481 in domain A are disoriented 20-35° from this orientation. However, if the full crystallographic
- 482 orientation is considered, the spread of orientations is significantly greater. Figure 7b shows the full
- 483 orientation deviation for each measurement away from the average orientation for crystallites in
- 484 domain B, once again up to a maximum of 45°. Now the spread of orientations within domain B
- extends to $>30^\circ$, with those points in domain A up to 45° disoriented.





487 Figure 7. Maps showing local and intra-crystalline orientation variations in the enamel, as measured 488 by TKD. (a) Texture map showing the deviation in c-axis orientations (up to 45°) from the average c-489 axis orientation within domain B. The histogram below shows the frequency distribution of all c-axis 490 deviations, with an x-scale from 0 - 45°, and highlights the differences between domain A (red) and 491 domain B (blue). (b) Texture map showing the absolute orientation deviation (up to 45°) from the 492 average orientation within domain B. The histogram below shows the frequency distribution of all 493 orientation deviations, with an x-scale from $0 - 45^{\circ}$. (c) A grain relative orientation deviation (GROD) 494 map highlighting the intracrystalline orientation within each grain / crystalline. The deviation of each

- 495 measurement from that grain's average orientation is plotted, up to a maximum of 8.25° and the
- 496 frequency distribution for all measurements is shown in the histogram below. The scale bar in each
- 497 *image marks* $1 \mu m$.
- 498 Within each crystallite (defined as areas bounded by boundaries with disorientations > 5°) there is
- 499 also significant variation in orientation, as shown in Figure 7c. Here the average orientation of each
- 500 crystallite is taken as a reference orientation, and then the disorientation between the reference and
- 501 each measured orientation is plotted (sometimes referred to as a grain relative orientation deviation
- 502 (GROD) map). Although most crystallites only have 1-2° of orientation deviation, many of the more
- 503 elongate crystallites in the upper part of domain B have higher internal orientation deviations,
- 504 frequently in the 3-6° range.
- 505 The crystallite size was determined using a threshold disorientation angle of 5° and a minimum size
- of 5 pixels, and the results are presented in Table 1. The statistics are presented for the whole
- 507 dataset, as well as domains A and B individually. In total 1103 crystallites were detected, with a
- 508 mean size (area-weighted equivalent circle diameter) of 129 nm. The crystallites have, on average, a
- high aspect ratio of 2.5, but the aspect ratio is significantly higher for domain B (2.62) than domain A
- 510 (2.1). As seen in the orientation map (Figure 5c) the long axes of crystallites in domain B are oriented
- 511 at a shallower angle to the map X direction than those in domain A.
- 512

	Number	Mean Area Weighted Equivalent Circle Diameter (nm)	Mean Aspect Ratio	Mean Length of Major Axis (nm)	Mean Length of Minor Axis (nm)	Average Angle between Major Axis and Map X direction
Whole Dataset	1103	129 ± 1.1	2.51 ± 0.04	155 ± 2.7	64 ± 0.7	24.2°
Domain A	261	108 ± 1.7	2.1 ± 0.06	126 ± 4.1	63 ± 1.2	37.6°
Domain B	847	134 ± 1.4	2.62 ± 0.05	163 ± 3.3	65 ± 0.8	20.1°

513 **Table 1.** Table showing grain measurements (with standard errors) from the TKD dataset, with grains

514 defined by a boundary disorientation of >5°. Grains belonging to domains A and B (as defined in

- 515 Figure 5c) are measured separately. Note that some grains are counted as being in both domains A 516 and B.
- 517 TEM imaging of the sample following TKD mapping highlights the dominant HAp crystallite 518 structures, with a preferred alignment of elongated crystallites within individual domains in the TEM 519 foil (Figure 8). The area analysed by TKD is characterised by discrete damage spots which are visible 520 in the lower right corner of Figure 8a, and on the right edge of the higher magnification image in 521 Figure 8b. These brightfield images show the different crystallite grain morphologies within each 522 domain, and the boundary between the domains can be readily traced (as approximately shown by 523 the red dashed lines in Figure 8, manually drawn based on the crystallite c-axis orientations). In the 524 higher magnification image (Figure 8b) the crystallites appear to be 100s nm long and typically 50-525 100 nm wide. However, the part of the TKD orientation map shown in Figure 8c (which aligns directly 526 with the damage spots on the right of Figure 8b) shows that the true crystallite size is significantly 527 larger than appears in the TEM image. Most of the crystallites measured by TKD contain low angle 528 boundaries (marked by grey lines in Figure 8c) which are typically aligned with their long axes, 529 indicating that many of the structures visible in the TEM images are likely to be "crystallites" or

subgrains that are disoriented by only a few degrees from their neighbours (and would thus not be

531 classed as separate grains, separated by high angle grain boundaries).



532

533 **Figure 8.** (a) Brightfield TEM image of part of the enamel sample, showing the overall crystallite

534 structure. The TKD area of analysis is marked by the white box in the lower right corner and the

535 damage spots. (b) Higher magnification TEM brightfield image, rotated so as to be aligned with the

536 TKD analysis area. The white damage spots on the right of the image indicate the TKD measurement

537 locations, as shown in the higher magnification inset. (c) A part of the TKD orientation map

538 (following data cleaning) using the IPF-Z colouring scheme (inset). Black and grey lines mark high

angle (>10°) and low angle (2-10°) boundaries respectively. The left edge of the map area aligns with

540 the left edge of the damage spots visible in (b). In all images the scale bars mark 500 nm and the red

541 dashed lines indicate the approximate border between domains A and B.

542

543 **4. Discussion**

544 4.1 TKD Analysis of Biomineralised HAp

545 A full crystallographic analysis of dental enamel structures using electron diffraction in the SEM 546 requires a combination of high spatial resolution and reliable diffraction pattern indexing methods. 547 Although previous work (27-28; Koblischka-Veneva et al., 2018; 2019) has highlighted the potential 548 of the TKD method for enamel characterisation, the data provided in that work does not stand up to 549 qualitative interrogation, as explained in the introduction. There are 2 clear challenges for the 550 reliable characterisation of HAp crystallites – the extreme beam sensitivity of the HAp structure and 551 the generally poor quality of any resulting diffraction pattern. TKD has been shown to deliver the 552 required spatial resolution for effective mapping of HAp crystallites, but conventional Hough-based 553 indexing methods do not give robust results, due to the lack of sufficiently well-defined Kikuchi 554 bands in each individual TKD pattern. Most Hough-based indexing approaches require the correct 555 identification of at least 6 Kikuchi bands in each pattern in order to give robust indexing results; 556 although the higher-quality patterns in these data (as exemplified in Figure 3a) can be successfully 557 indexed via the Hough-transform method, most patterns lack the required signal to noise ratio or 558 Kikuchi band definition for reliable indexing in this way. Pattern matching methods do not suffer 559 from this drawback: the indexing is based on the pixel-to-pixel correlation between the experimental 560 pattern and a simulated pattern, so does not require well-defined Kikuchi bands for successful 561 interrogation. The increase in indexing rate over Hough-based indexing, from 29.1% to 71.8%, 562 demonstrates the efficacy of the dynamic template matching indexing method employed in this 563 study. We have demonstrated that, following further minor cleaning of the data, it is possible to

- 564 characterise effectively the detailed crystallite structure, the full orientation at each point and the
- 565 intra- and inter-crystallite boundaries within dental enamel. This has not been effectively
- 566 demonstrated previously and opens the door to a more thorough interrogation and understanding
- 567 of the HAp structures in dental enamel.

However, even with dynamic template matching, there are TKD patterns that could not be reliably 568 569 indexed: this is particularly true at the lower part of the analysis area, where the increased thickness 570 of the FIB lamella results in greater electron scattering through the sample, a corresponding increase 571 in the TKD pattern source volume and a subsequent drop in the pattern sharpness and quality (e.g. 572 Figure 4 and Figure 5a). One of the strengths of pattern matching methods is that they can provide a 573 best-fit solution for any acquired pattern, regardless of the pattern quality. However, this also can be 574 one of the weaknesses of the method – without a suitable minimum threshold for the image 575 similarity (between the experimental and simulated patterns), incorrect solutions would be obtained 576 for the poorest patterns in any dataset. Here, the acceptance of solutions that give a normalised 577 cross correlation coefficient > 0.15 minimises this risk, but for any pattern matching method the 578 setting of such a threshold remains critical for a robust microstructural characterisation. Adjusting 579 the R threshold to a higher value (e.g. R = 0.2) would reduce the indexing success rate, but eliminate most if not all falsely indexed points; likewise a lower R threshold (e.g. R = 0.1) would result in a 580 581 higher indexing success rate but at the expense of data reliability. The selected value of R = 0.15 582 provides a suitable balance between the two, with almost all false solutions corrected during the

583 final stage of the pattern matching process (the "Repair Sweep", Figure 2, Step 16).

584 4.2 The Impact of Beam Damage to HAp Crystallites during TKD Analyses

The spatial resolution demonstrated by the TKD data shown here, with a 20 nm measurement step 585 586 size, is sufficient for the characterisation of all but the very smallest HAp crystallites. However, the 587 beam sensitivity of the HAp crystallites is clear from the damage visible in the TEM images after the 588 TKD analysis (Figure 8). Each damage spot is approximately 2-3 nm across, although occasionally the 589 damage is more extensive, in the 5-10 nm diameter range. With a 20 nm step size, these damage 590 spots do not overlap (as visible in Figure 8b) and subsequently there is no progressive accumulation 591 of damage as the TKD analysis is carried out. Therefore, with these beam conditions and pattern 592 exposure times, we would expect a lower limit for the measurement step size to be in the range of 593 10-15 nm, below which damage would accumulate from point to point or row to row, reducing the 594 quality of the TKD data. For the data presented here, the electron dose at each point was 420 nAms 595 (3.9 nA beam current x 108 ms exposure); this is a relatively high dose required in part by the weakly 596 diffracting nature of HAp, but also due to the inefficiency of the TKD geometry. Across the whole mapped area, this dose equates to $\sim 6.5 \times 10^4 \text{ e}^{-}/\text{Å}^2$, which is towards the upper levels of electron 597 598 doses in previous TEM-based studies of irradiation damage of apatite crystals (e.g. 47-48; Brès et al., 599 1991; Meldrum et al., 1997). However, the characteristics of a TKD analysis in the SEM is significantly different from TEM imaging. Standard TEM imaging exposes the whole imaged area to a uniform 600 601 dose, whereas in TKD mapping the beam is focused into discrete spots, the size of which is 602 dependent on the diameter of the focused electron beam (although scattering of electrons through 603 the sample thickness will result in a slight broadening of the interaction volume). For a high-604 performance FEG-SEM, as used in this study, it is reasonable to assume that the beam diameter will 605 be approximately 2 nm: therefore the electron dose is extremely high (e.g. $\sim 8 \times 10^6 \text{ e}^{-1}/\text{Å}^2$) at these 606 discrete analysis spots but is negligible in the surrounding material. In this study, with a 607 measurement spacing of 20 nm, this means that ~ 99% of the surface area will have negligible direct 608 dose (these areas will be exposed to the electron beam only during initial imaging, when FSD images 609 were collected with a dwell time per pixel of 60 μ s, giving a dose of ~ 0.4 e /Å²).

610 A reduction of the electron dose, whilst maintaining the same quality of TKD pattern, would enable a 611 smaller measurement step size and thus a higher spatial resolution of the analyses. This could be 612 achieved by positioning the EBSD detector closer to the sample (here the detector distance, the 613 distance from the electron beam – specimen interaction point and the detector phosphor screen, 614 was 14.1 mm), using an alternative TKD geometry (e.g. on-axis TKD) or by improving the sensitivity 615 of the EBSD detector. Although pattern matching indexing methods, such as dynamic template 616 matching, do enable successful indexing of poorer quality TKD patterns (e.g. collected using a lower 617 electron dose), the reliability of the data would decrease and there would be more systematic 618 indexing errors resulting from the pseudosymmetry of the HAp structure. There is the possibility that 619 a lower electron dose would lessen the localised damage to the HAp structure and therefore 620 maintain or improve the TKD pattern quality, but in testing on these samples this was not observed. 621 Once again, the importance of setting of an appropriate pattern matching quality threshold is critical 622 for ensuring the integrity of data derived from pattern matching interrogation of biomineralised HAp

623 structures.

624 Based on the difference between enamel HAp crystallite sizes measured using TKD mapping in this 625 study and those reported in earlier TEM-based studies (e.g. 4; Kerebel et al., 1979), especially taking 626 into account the high electron dose used here, it must be considered whether beam damage to the 627 HAp structure is affecting the reliability of the results. It is well established from previous TEM 628 studies that damage in dental enamel HAp can occur in a number of ways, including void formation, 629 amorphisation and crystallisation of CaO or CaF₂ (e.g. 47-48; Brès et al., 1991; Meldrum et al., 1997). 630 However, as previously mentioned, the characteristics of TEM imaging and TKD analyses differ 631 significantly: it is to be expected that, at the point of each TKD analysis, significant damage will be 632 caused to the HAp structure. However, there are two key points to consider when comparing to 633 previous TEM studies. Firstly, the damage will be limited to the electron-sample interaction volume 634 and its immediate surrounds, as shown by the discrete nature of the damage spots visible in Figure 635 8b. Image analysis of the damage spots in the TEM images show that these make up \sim 4 % of the total TKD analysis area. Secondly, the TKD pattern that is collected at each point is an integration of 636 637 the signal for the whole dwell time at that point; therefore, even if the HAp was being damaged 638 during this process, the initial diffraction signal would likely be strong and this would decrease 639 during the pattern acquisition time (approximately 100 ms) as the crystal structure deteriorates, 640 resulting in a progressively increased level of noise in the pattern and a corresponding drop in the 641 final cross correlation coefficient following pattern matching. However, the initial higher-intensity 642 diffracted signal would likely still dominate the final TKD pattern, ensuring robust orientation 643 measurements.

In order to investigate potential damage during TKD analyses in more detail, an area of the sample (covering part of the original TKD map area and part that had not been previously analysed) was remapped at a higher spatial resolution (10 nm measurement spacing) and compared to the prior TEM images. Figure 9 shows the results of this subsequent analysis, although note that this was carried out with the sample mounted upside down compared to the previous TKD analysis and thus it is impossible to carry out a direct correlation of the mapped HAp structures. There are a number of conclusions that can be drawn from this follow-on analysis:

The damage from the initial TKD mapping is almost invisible in the subsequent map results,
 with only a slight decrease in TKD pattern quality resulting in a barely-discernible drop in the
 subsequent cross correlation coefficient values (Figure 9b). If a subsequent measurement
 spot was positioned over one of the pre-existing damage spots, then it would likely result in

- 655a significantly reduced TKD pattern quality and a corresponding drop in the cross correlation656value.
- 657 Within the TEM image, there are some clear boundaries and crystallites that can be traced • 658 across the border of the original TKD map area, which would indicate that there was no 659 structural modification caused by the initial TKD mapping process. These boundaries and crystallites also appear continuous across the edge of the original TKD map area in the 660 661 subsequent TKD map data, once again confirming that the original analysis has not altered 662 the HAp grain structure (as shown by the arrowed boundary in Figure 9). It is, however, clear that the HAp structure at the nm-scale has been affected, likely by either amorphisation of 663 the crystalline lattice or by void formation (resulting in the clear damage spots in Figure 9a), 664 665 but there is no evidence for this altering the grain-scale structures on the 10s to 100s nm scale. In addition, there is no evidence for any change in crystallographic orientation across 666 667 the border between the originally mapped area and the adjacent region (as shown in Figure 9c), confirming that, if there was any change in orientation caused by the electron beam -668 669 HAp interaction, then it is at a level below that detectable using the TKD pattern matching 670 technique (e.g. $< 0.1^{\circ}$).
- There is no apparent change in the TEM image contrast or crystallite structure within and
 outside the originally mapped area, with the exception of the individual damage spots. This
 would indicate that the majority of the structure has not been modified by the TKD mapping.
 - There is no evidence of crystallisation of the cubic CaO or CaF₂ phases. In all areas of this remapped region, pattern matching results were consistent with the structure remaining as crystalline HAp.



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- Figure 9. Results of a follow-on TKD analysis across the edge of the originally mapped area, using a
- 679 smaller 10 nm step size. (a) Brightfield TEM image, showing the damage spots from the first TKD
- 680 analysis. The yellow box marks the area of the subsequent TKD analysis. (b) Normalised cross
- 681 correlation coefficient map of the TKD results, with the scale ranging from R = 0.1 (black) to R =
- 682 0.6178 (white). (c) Inverse pole figure (z-direction) orientation map of the same area, with high angle
- 683 boundaries shown in black, boundaries with 30° rotations about <0001> in red and low angle
- 684 boundaries in grey. In both (b) and (c), the edge of the original TKD analysis area is marked by the
- 685 yellow dashed line. The red arrows mark a boundary that is clearly visible in all the images, and the
- labels A and B in (c) mark the domains visible in the previous analyses (e.g. Figure 5). The scale bar in
- 687 (a) marks 500 nm and all images are displayed at the same scale.
- These observations support the argument that, although there is localised damage, this is notaffecting the reliability of the TKD orientation measurements.

690 4.3 Comparison with TEM Imaging

691 The comparison with TEM imaging is particularly revealing, as shown in Figure 8. The morphology of 692 crystallites is very clear in the TEM images, allowing a simple identification of the 2 domains based 693 on the orientation of the crystallite long-axes (e.g. Figure 8a). However, the direct comparison 694 between the TKD orientation map (Figure 8c) and the TEM brightfield image of the immediately 695 adjacent area (Figure 8b) shows that the crystallite size, as determined from the TEM image, appears 696 much smaller than in the TKD map. Although there was minor drift during the TKD analysis, this 697 amounted to only 5.7 % in the y-direction and cannot explain the crystallite size discrepancy 698 between TKD and TEM. A closer inspection of the TKD map shows that there are multiple low angle 699 boundaries (grey lines in Figure 8c, representing crystallographic disorientations of 2-10°) and that 700 these delineate areas of a similar scale to those visible in the TEM images (i.e. 40-80 nm width, 100s 701 nm length). This is also visible in the absolute orientation deviation texture map (Figure 7b) in which 702 the subtle, low-angle orientation changes between adjacent crystallites are apparent. The same 703 observations are apparent in the follow-on TKD results, shown in Figure 9, although here the 704 normalised cross correlation map does suggest a crystallite size closer to that inferred from the TEM 705 image and reported in other TEM-based studies (e.g. 49, DeRocher et al., 2020). These observations 706 indicate that many of the crystallites in the TEM image have a crystallographic orientation very close 707 (< 10°) to that of their neighbours. In addition, the GROD map (Figure 7c) highlights that many of the 708 crystallites also contain significant lattice distortion on the sub-100 nm scale. Although most 709 crystallites have minimal variation in crystallographic orientation (< 1°, as indicated by dominantly 710 white shades in Figure 7c), there are many cases where the distortion extends into the 2-4° range: 711 the crystallites, as viewed in the TEM images are essentially "sub-grains" with a significant amount of 712 intra-crystallite distortion. The subdivision of larger, perfect crystallites into smaller domains with 713 slight variations in crystallographic orientation has been referred to as "crystal splitting" (e.g. 50; 714 Deng et al., 2022). Similar structures have been commonly observed in many biomineralised 715 materials, including in the calcite (CaCO₃) shells of oysters as revealed by 3D X-ray Bragg 716 ptychography (51; Mastropietro et al., 2017), and may be interpreted as a strengthening mechanism 717 or as a direct consequence of the biomineralisation process.

718 The difference in grain size between that measured using TKD orientation measurements and that 719 inferred from TEM images is not unique to HAp or to biomineralised samples. In many highly 720 deformed materials, including metals and minerals, the inferred grain size from TEM imaging is 721 consistently smaller than that measured using TKD. This is demonstrated in Figure 10, which shows a 722 brightfield TEM image and a TKD orientation map from the same area in a highly-deformed Al-Mg-Cu 723 alloy (processed with 4 passes of equal channel angular pressing (ECAP) performed at room 724 temperature). The TEM brightfield image of the matrix region (Figure 10a) can be interpreted as 725 showing a nanocrystalline grain structure, yet the TKD orientation map (Figure 10b) shows that 726 many grains are 1-5 µm long and made up of multiple, smaller domains with low angle 727 disorientations (< 5°) between them, as marked by grains 1 and 2 in both images. These slight 728 changes in crystallographic orientation can produce significant changes in the TEM image signal but 729 should not be interpreted as representing different grains. In the same way with the HAp dental 730 enamel structures, the TEM images suggest a very small crystallite size, in the order of a few 10s nm, 731 yet many adjacent crystallites share very similar crystallographic orientations and, when measured 732 using TKD, the true grain sizes (as defined as areas bound by higher angle boundaries, > 5°) are 733 significantly larger (Table 1). Such differences can be attributed to the quantitative nature of TKD 734 orientation maps, as well as the difference in information source volumes for the 2 techniques. It has 735 been well documented that the TKD pattern is dominantly derived from the lower (exit) surface of 736 the sample, enabling the resolution of crystallites that are significantly smaller than the sample

- thickness (e.g. 22-23; Keller and Geiss, 2012; Trimby, 2012). This is in contrast to TEM imaging where
- the signal is derived from the full sample thickness.
- These factors explain the apparent discrepancy between the results presented in this work and TEM-image based results from previous studies of dental enamel.



- 742 Figure 10. Comparison between TEM brightfield imaging and TKD orientation mapping of a room
- temperature deformed aluminium alloy. (a) Brightfield TEM image collected at 200 kV, showing a
- 744 large deformed grain within what appears to be a nanocrystalline matrix. (b) TKD orientation map of
- the same area (collected with an 8 nm measurement spacing) showing that the matrix is mostly
- 746 comprised of long, elongate grains with significant substructure. Black lines indicate boundaries > 10°
- 747 *disorientation, grey lines boundaries between* 2° *and* 10° *disorientation, colours use the inverse pole*
- figure colour scheme for the sample normal direction (inset). Scale bars in both images mark 1 μm,
 with "1" and "2" marking the same elongate grains in both images. See text for discussion.

750

751 4.4 New Insights into Enamel HAp Structure using Complete Orientation Measurements

The TKD results presented here have a significant advantage over other widely-used methods for
 characterising HAp crystallites in dental enamel, namely the measurement of the full 3-dimensional
 crystallographic orientation. This enables a more rigorous examination of the true crystallite size, the

relationship between crystallite morphology and crystallographic orientation and the absolute localorientation variations.

757 The fact that the TKD measurements determine not just the c-axis orientation of the HAp crystal 758 lattice (as is common with many alternative techniques), but the full crystallographic orientation, 759 reveals a number of important observations about the enamel microstructure. Firstly, the extent of 760 orientation variation from crystallite to crystallite is significantly greater than would be measured by 761 c-axis orientations alone, as shown by the comparison between Figures 7 (a) and (b). Relative to the 762 average orientation in Domain B, the c-axes within this domain vary in orientation by up to \sim 15°, but 763 the full crystallographic orientation varies by up to ~30° - this increased level of orientation variation 764 will have a significant impact on the expected physical properties of the enamel. Additionally, the full 765 crystallographic orientation data highlights the systematic rotation between adjacent crystallites of 766 30° about the <0001> axis, as shown in Figures 5c and 6. These special boundaries, which would not 767 be visible if only the c-axis orientations were measured, may represent a type of twin boundary. It is 768 well understood from the study of metals and geological minerals that twins can form either as

- 769 growth twins or in response to deformation, and both growth twinning in biogenic aragonite and
- deformation twinning in biogenic calcite have been widely reported (e.g. 52-54; Mukai et al., 2010;
- Pokroy et al., 2007; Côté et al., 2015). Twinning in enamel HAp has also been widely reported, but
- these previously-identified twin boundaries typically form straight features aligned with the long axis
 of the HAp crystallites (i.e. parallel to the c-axis direction) (55-56; Rachinger et al., 1982; Brès et al.,
- 1986). In the TKD data presented here, the boundaries with the aforementioned 30° about <0001>
- rotation form irregular interfaces between adjacent clusters of slightly-disoriented crystallites (red
- boundaries in Figure 5c). This morphology is not characteristic of most twinned structures, either
- 777 caused by growth or deformation, suggesting that these may not be true twin boundaries but are,
- perhaps, indicative of a systematic switch in crystallite orientation during biomineralisation that may
- benefit the bulk physical properties.
- 780 There have been many studies that have inferred that the hierarchical structures visible in
- biomineralised HAp in dental enamel result in the exceptional physical properties of the enamel
- 782layer (57-58, 13; Koenigswald et al., 1992; Wegst et al., 2014; Stifler et al., 2021). The misorientation
- between adjacent HAp crystallites has been correlated with improved crack-deflection, although
- once again previous studies have only focused on the variation of c-axis orientations (e.g. 13; Stifler
- et al. 2021). The results shown here highlight the importance of measuring the full crystallographic
- orientation, as previous work neglects the role of any misorientations that involve a component of
- rotation about the HAp c-axes. These include the anomalously abundant boundaries with rotations
- close to 30° about <0001>, but also the smaller disorientations within and between crystallites that
- are highlighted in Figures 7 (b) and (c). An accurate measurement of the full, true degree of crystal
- 790
 lattice orientation variation is necessary to understand the true importance of the hierarchical
- 791 structures and their role in determining the enamel's physical properties.

792 4.5 Future Work

793 The method and results presented here represent a proof of concept of the potential of TKD 794 analyses, in combination with novel pattern matching methods, for the effective characterisation of 795 HAp nanostructures in biomineralised materials such as dental enamel. The high spatial resolution 796 coupled with the measurement of the full crystallographic orientation makes this a unique and 797 powerful approach, without necessitating time on expensive beamlines. It is not possible to make 798 justified statements on the detailed hierarchical structures visible in this dental enamel sample, or 799 even to interpret the nature of the domain boundary visible in these results (e.g. whether this is the 800 boundary between an adjacent prism tail and head) - for this, further analyses of multiple, larger 801 areas of TEM samples will be necessary. This will be the focus of future work on similar dental 802 enamel samples, with a correlation to the larger scale hierarchical structures and to the resulting 803 mechanical properties. As a potential avenue for future research, the analysis of the cross-sectional 804 plane of prisms, rather than their long axes, could prove to be a valuable approach for investigating 805 the structure and properties of dental enamel. By examining the cross-sectional plane, it may be 806 possible to gain a deeper understanding of the orientation and distribution of the HAp crystallites 807 within the whole prism cross-section, as well as their potential role in the mechanical properties of 808 enamel.

809

810 **5. Conclusions**

811 We present the first effective characterisation of HAp microstructures in human dental enamel using

812 the SEM-based TKD technique coupled with newly-developed pattern matching methods, including

- 813 dynamic template matching and subsequent orientation refinement. This approach delivers high
- spatial resolution measurement of the absolute crystallographic orientation of the HAp crystallites,
- 815 with a significantly improved data quality compared to conventional Hough-transform based
- 816 indexing methods. Although localised damage to the HAp crystal structure has occurred during the
- TKD analysis, we have shown that this has not affected the veracity of the TKD results. The TKD
- 818 orientation measurements have been subsequently compared to TEM images of the same and
- adjacent areas, revealing some key differences between the results from both techniques.
- The results highlight a number of interesting features of the HAp microstructure within the studiedenamel sample:
- Many of the crystallites, as detected in the TEM brightfield images, are only slightly
 disoriented (e.g. <10°) from adjacent crystallites. The true grain size within the enamel layer
 (as determined by high angle grain boundaries) is thus significantly greater than would be
 deduced from the TEM images alone.
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- 828 3. Within individual domains in the enamel, there is a strong clustering of c-axis orientations
 829 (up to ~15° deviation from the average c-axis orientation within each domain), but a greater
 830 deviation of the full crystallographic orientation (up to ~30°).
- 831 4. Many boundaries between adjacent crystallites have a rotation angle and rotation axis close
 832 to 30° about the <0001> axis. These boundaries are commonly irregular in morphology so
 833 may not be true twin boundaries.
- 834 The capability of the TKD method, in conjunction with pattern matching reanalysis, to determine the 835 full crystallographic orientation of the HAp crystal lattice, and not just the c-axis orientation (as with 836 many other analysis methods) enables a far more rigorous examination of the crystallographic 837 characteristics of the enamel microstructure. This additional information will help us to understand 838 better the relationship between enamel's remarkable physical properties and the crystal structure of 839 the HAp on the nanoscale, using tools widely available to many researchers. We expect to further 840 refine this method and to apply it to a wider range of enamel samples in order to characterise better 841 the relationship between the HAp nanostructures and the known structural domains within human 842 dental enamel.
- 843

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